

## **Search Notes**



**Application/Control No.**

10/661,454

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**Examiner**

John P. Leubecker

**Applicant(s)/Patent under  
Reexamination**

PHAN, HUY D.

## Art Unit

3739

SEARCHED

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner